

<b>Notice of References Cited</b>	Application/Control No. 10/667,426	Applicant(s)/Patent Under Reexamination HIRUKAWA, SHUICHI	
	Examiner Phillip Nguyen	Art Unit 2828	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,821,806 B1	11-2004	Takahashi et al.	438/46
*	B	US-6,764,926	07-2004	Takeuchi et al.	438/477
*	C	US-6,541,297	04-2003	Takahashi, Koji	438/31
*	D	US-6,670,643	12-2003	Hirukawa, Shuichi	257/79
*	E	US-RE38,072	04-2003	Kondo et al.	438/47
*	F	US-2004/0041162 A1	03-2004	Shimoyama et al.	257/091
*	G	US-6,879,614	04-2005	Sato, Shunichi	372/45.01
*	H	US-6,233,264	05-2001	Sato, Shunichi	372/45.01
*	I	US-6,821,806	11-2004	Takahashi et al.	438/46
*	J	US-6,815,731	11-2004	Sato, Shunichi	257/103
*	K	US-5,210,767	05-1993	Arimoto et al.	372/46.01
*	L	US-2002/0125489 A1	09-2002	Sato, Shunichi	257/86
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.